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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
. 10/789,055	02/27/2004	Min Ho Jung	30205/37328A	9165
4743	7590 07/15/2005		EXAMINER	
	L, GERSTEIN & BOR KER DRIVE, SUITE 630	. LEE, SIN J		
SEARS TOW	-	•	ART UNIT	PAPER NUMBER
CHICAGO,	IL 60606		1752	
		DATE MAIL ED: 07/15/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

				(in			
Office Action Summary		Application No.	Applicant(s)				
		10/789,055	JUNG ET AL.				
		Examiner	Art Unit				
		Sin J. Lee	1752				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply							
THE - Ext afte - If th - If N - Fai Any	HORTENED STATUTORY PERIOD FOR IT MAILING DATE OF THIS COMMUNICAT ensions of time may be available under the provisions of 37 (or SIX (6) MONTHS from the mailing date of this communicate period for reply specified above is less than thirty (30) days to period for reply is specified above, the maximum statutory lure to reply within the set or extended period for reply will, by reply received by the Office later than three months after the property of the prope	ION. CFR 1.136(a). In no event, however, may a jon. s, a reply within the statutory minimum of th period will apply and will expire SIX (6) MC a statute, cause the application to become A	a reply be timely filed hirty (30) days will be considered timely. DNTHS from the mailing date of this communicati ABANDONED (35 U.S.C. § 133).	ion.			
Status							
1)	Responsive to communication(s) filed on	27 February 2004		•			
2a)[_		This action is non-final.					
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Disposi	tion of Claims						
5)□	Claim(s) <u>13-16 and 21-28</u> is/are pending 4a) Of the above claim(s) is/are wi Claim(s) is/are allowed. Claim(s) <u>1-15,21 and 24-28</u> is/are rejected to. Claim(s) <u>16,22 and 23</u> is/are objected to. Claim(s) are subject to restriction	thdrawn from consideration.					
Applica	tion Papers						
	The specification is objected to by the Example The drawing(s) filed on 27 February 2004. Applicant may not request that any objection Replacement drawing sheet(s) including the of the oath or declaration is objected to by the specific terms of the specific terms	is/are: a)⊠ accepted or b)□ to the drawing(s) be held in abeya correction is required if the drawin	ance. See 37 CFR 1.85(a). g(s) is objected to. See 37 CFR 1.121	(d).			
Priority	under 35 U.S.C. § 119		•				
12)⊠ a	Acknowledgment is made of a claim for for All b) Some * c) None of: 1. Certified copies of the priority docu 2. Certified copies of the priority docu 3. Copies of the certified copies of the application from the International E	ments have been received. Iments have been received in the priority documents have bee Bureau (PCT Rule 17.2(a)).	Application No. <u>09/878,803</u> . n received in this National Stage	:			
* 55V.							
フ・ Attachme	nt(s)						
1) Noti 2) Noti 3) Noti	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-94 rmation Disclosure Statement(s) (PTO-1449 or PTO/8 er No(s)/Mail Date 6/4/04.	l8) Paper No	Summary (PTO-413) (s)/Mail Date Informal Patent Application (PTO-152) 				

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DETAILED ACTION

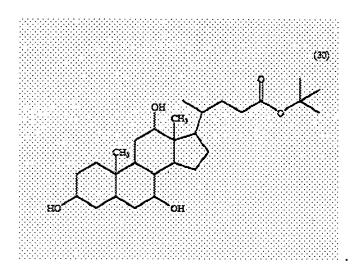
Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 13-15, 21, and 24-28 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kajita et al (US 6,180,316 B1) in view of applicants' admitted prior art (pg.1 lines 12-26 of present specification).

Kajita teaches a resist composition suitable for KrF excimer laser, exhibiting high transparency to radiation, superior dry-etching resistance, high resolution, and an excellent pattern configuration and sensitivity (see col.2, lines 60-67). Specifically, in Example 24, Kajita teaches a composition containing a copolymer, two photoacid generators (one of which is triphenylsulfonium trifluoromethanesulfonate), an alicyclic compound (C-3) which structure is shown below and a solvent which is ethyl 2-hydroxypropionate (see Table 1, col.48, lines 50-65, col.49, line 34, and Synthesis Example 17):

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The compound (C-3) meets Kajita's generic formula (5) shown in col.4, lines 17-36. Kajita teaches the equivalence of –OH groups and a H atom for R⁶ and R⁷ in his formula (5). Kajita also teaches the equivalence of –OH group and an alkyl carbonyloxy group having 2 carbon atoms (-O-C(=O)-CH₃) for R⁵ in his formula (5). Therefore, based on Kajita's teaching, it would have been obvious to one skilled in the art to replace those two -OH groups (in R⁶ and R⁷ positions) in Kajita's compound (C-3) with H atoms and replace the -OH group (in R⁵ position) in Kajita's compound (C-3) with -O-C(=O)-CH₃ with a reasonable expectation of obtaining a resist composition suitable for KrF excimer laser, exhibiting high transparency to radiation, superior dry-etching resistance, high resolution, and an excellent pattern configuration and sensitivity. Therefore, Kajita' teaching renders obvious present compound of Formula 2 of claim 21.

Kajita prepares a resist pattern from his composition by applying his resin composition onto a silicon wafer, imagewise exposing to radiation such as KrF excimer laser, and then developing the exposed areas on the resist film (see col.23, lines 18-28, lines 48-49). Therefore, Kajita teaches present invention of claim 1 except for the

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present resist flow process. Present specification, pg.1, lines 14-26 states that resist flow is a processing technology for forming a fine contact hole which exceeds the resolution of the exposing device. It also states that the resist flow process involves an exposure process and a development process and then heating the photoresist to a temperature higher than the glass transition temperature of the photoresist, which causes the photoresist to flow until a fine contact hole necessary for the integration process is obtained. Applicants also state that most of the KrF resist can be flow processed. Since Kajita's composition is a KrF resist, and since Kajita states that his resist composition exhibits high resolution and an excellent pattern configuration, it would have been obvious to one skilled in the art to use Kajita's photoresist in the art-known resist flow technology in order to form a fine contact hole which exhibits high resolution and an excellent pattern configuration. Therefore, Kajita in view of applicants' admitted prior art would render obvious present inventions of claims 13-15, 21, and 25.

With respect to present claim 24, Kajita's Example 24 uses 20 parts by weight of the compound C-3 for 80 parts by weight of the compound. Thus, Kajita in view of applicants' admitted prior art would render obvious present invention of claim 24.

With respect to present claim 26, Kajita's Example 24 uses 2.4 parts by weight of the photoacid generators for 80 parts by weight of the copolymer, which gives 3% by weight of the photoacid generators. Thus, Kajita in view of applicants' admitted prior art would render obvious present invention of claim 26.

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With respect to present claim 27, Kajita teaches the equivalence of ethyl 2-hydroxypropionate and propylene glycol monomethyl ether acetate as his solvent.

Therefore, it would have been obvious to one skilled in the art to use propylene glycol monomethyl ether acetate as Kajita's solvent in his Example 24. Thus, Kajita in view of applicants' admitted prior art would render obvious present invention of claim 27.

With respect to present claim 28, Kajita's Example 24 uses 533 parts by weight of the solvent for 80 parts by weight of the copolymer, which gives 666% by weight of the solvent. Thus, Kajita in view of applicants' admitted prior art would render obvious present invention of claim 28.

Allowable Subject Matter

- 3. Claims 16, 22, and 23 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims. Kajita does not teach or suggest present temperature range of claim 16 for the resist flow process. Kajita does not teach or suggest present photoresist polymers of claims 22 and 23.
- 4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sin J. Lee whose telephone number is 571-272-1333. The examiner can normally be reached on Monday-Friday from 9:00 am EST to 5:30 pm EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cynthia Kelly, can be reached on 571-272-1526. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

S-J.L.

S. Lee July 10, 2005 SIN LEE PRIMARY EXAMINER